

Notice of References Cited	Application/Control No.	Applicant(s)/Patent Under Reexamination	
	10/670,787	HAN ET AL.	
	Examiner Jason M. Han	Art Unit 2875	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
	D	US-			
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	G	US-			
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	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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	N	JP2000162593A	06-2000	Japan	Nishiyama et al.	G02F 1/1335
	O					
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NON-PATENT DOCUMENTS

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